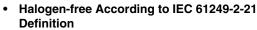


RU40120M-VB Datasheet N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)		
40	0.0025 at V _{GS} = 10 V	120	38 nC		
40	0.0028 at V _{GS} = 6.5 V	105	36 110		

FEATURES

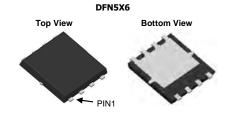


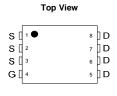


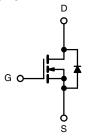
- Trench Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- Synchronous Rectification
- Secondary Side DC/DC







N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	40	V		
Gate-Source Voltage		V _{GS}			± 20
	T _C = 25 °C		120		
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	I _D	80		
	T _A = 25 °C	υ.	33 ^{b, c}		
	T _A = 70 °C		26 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	360		
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	100		
Continuous Source-Drain Diode Guirent	T _A = 25 °C	'S	4.9 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	40		
Single Pulse Avalanche Energy	L = 0.1 11111	E _{AS}	80	mJ	
	T _C = 25 °C		83		
Maximum Power Dissipation	T _C = 70 °C	P _D	53	w	
Maximum Fower Dissipation	T _A = 25 °C	, р	5.4 ^{b, c}	7 "	
	T _A = 70 °C		3.4 ^{b, c}		
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Temperature	_	260			

THERMAL RESISTANCE RATINGS								
Parameter		Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	18	23	°C/W			
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	1.0	1.5	- C/VV			

- a. Based on T_C = 25 °C.
 b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 80 A.



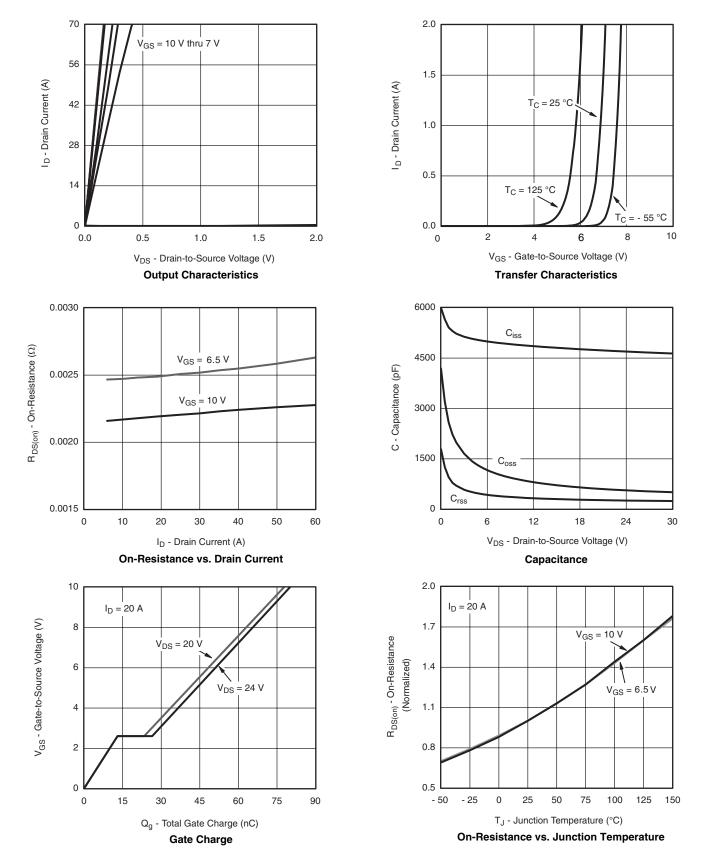
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						1
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	40			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 vA		43		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
		V _{DS} = 40 V, V _{GS} = 0 V			1	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 40 V, V _{GS} = 0 V, T _J = 55 °C			10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	100			Α
		V _{GS} = 10 V, I _D = 20 A		0.0025		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} =6.5 V, I _D = 20 A		0.0028		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 20 A		102		S
Dynamic ^b						
Input Capacitance	C _{iss}			4750		pF
Output Capacitance	C _{oss}	V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHz		610		
Reverse Transfer Capacitance	C _{rss}			275		
Tatal Oats Observe		V _{DS} = 20 V, V _{GS} = 10 V, I _D = 20 A		78	117	
Total Gate Charge	Qg			38	57	nC
Gate-Source Charge	Q_{gs}	$V_{DS} = 20 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 20 \text{ A}$		13		
Gate-Drain Charge	Q_{gd}			11		
Gate Resistance	R_g	f = 1 MHz	0.2	0.7	1.4	Ω
Turn-On Delay Time	t _{d(on)}			14	25	-
Rise Time	t _r	$V_{DD} = 20 \text{ V}, R_L = 2 \Omega$		9	18	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		41	65	
Fall Time	t _f			9	18	
Turn-On Delay Time	t _{d(on)}			33	42	ns
Rise Time	t _r	V_{DD} = 20 V, R_L = 2 Ω		22	35	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		42	65	
Fall Time	t _f			13	25	
Drain-Source Body Diode Characteris	tics					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C		50		А
Pulse Diode Forward Current ^a	I _{SM}			60		
Body Diode Voltage	V_{SD}	I _S = 5 A		0.75	1.1	٧
Body Diode Reverse Recovery Time	t _{rr}			40	60	ns
Body Diode Reverse Recovery Charge	Q _{rr}	l _F = 10 A, dl/dt = 100 A/μs, T _J = 25 °C		48	72	nC
Reverse Recovery Fall Time	t _a	$\frac{1}{1}$ $\frac{1}$		24		200
Reverse Recovery Rise Time	t _b	7		16		ns

Notes

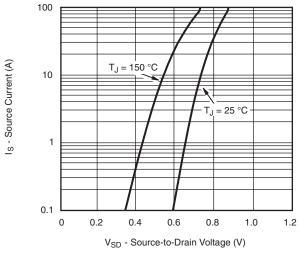
- a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.
- b. Guaranteed by design, not subject to production testing.

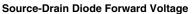
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

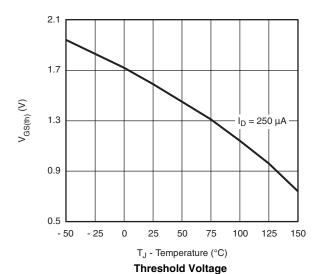


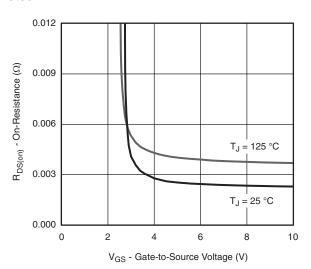




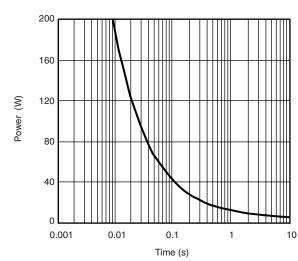




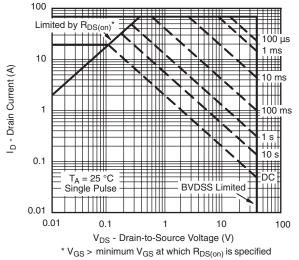




On-Resistance vs. Gate-to-Source Voltage

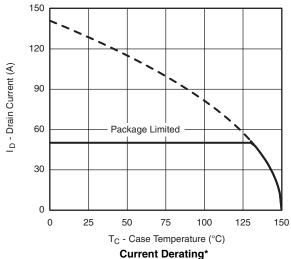


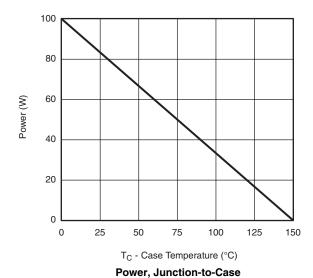
Single Pulse Power, Junction-to-Ambient

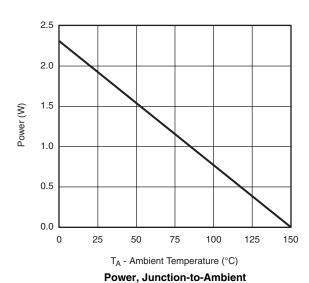


Safe Operating Area, Junction-to-Ambient



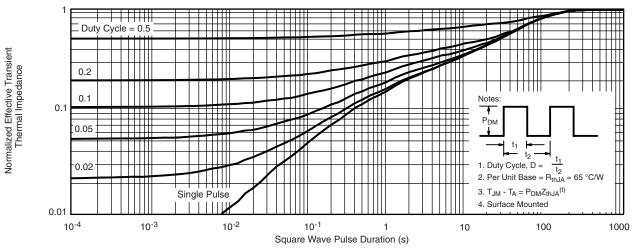


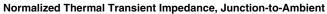


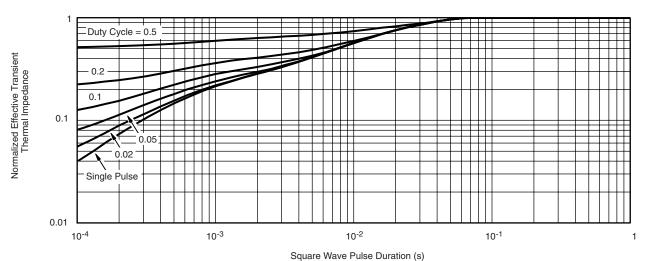


 $^{^*}$ The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





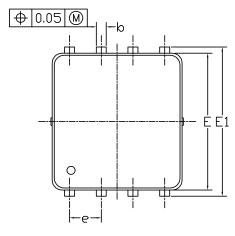


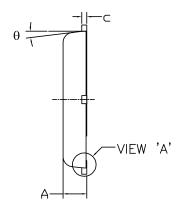


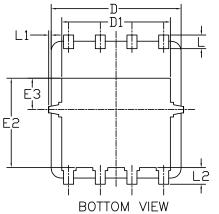
Normalized Thermal Transient Impedance, Junction-to-Case

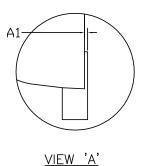


DFN5x6_8L_EP1_P PACKAGE OUTLIN



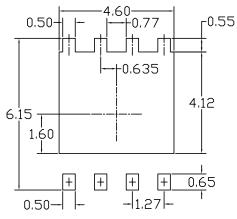






 $\frac{\text{VIEW} \quad A}{\text{(SCALE 5:1)}}$

RECOMMENDED LAND PATTERN



	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
A	0.85	0. 95	1.00	0.033	0.037	0.039
A1	0.00		0.05	0.000		0.002
b	0.30	0.40	0.50	0.012	0.016	0.020
С	0.15	0.20	0. 25	0.006	0.008	0.010
D	5. 10	5. 20	5. 30	0. 201	0. 205	0. 209
D1	4. 25	4. 35	4. 45	0. 167	0.171	0.175
Е	5. 45	5. 55	5. 65	0. 215	0. 219	0. 222
E1	5. 95	6.05	6. 15	0. 234	0. 238	0. 242
E2	3. 525	3. 625	3. 725	0. 139	0. 143	0. 147
E3	1. 175	1. 275	1. 375	0.046	0.050	0.054
e	1. 27 BSC			0.050 BSC		
L	0.45	0. 55	0.65	0.018	0.022	0.026
L1	0		0.15	0		0.006
L2	0.68 REF			0.027 REF		
θ	0°		10°	0°		10°

NOTE

- UNIT: mm
- 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
 MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH.
- 2. CONTROLLING DIMENSION IS MILLIMETER. CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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